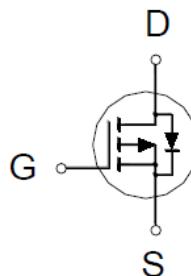
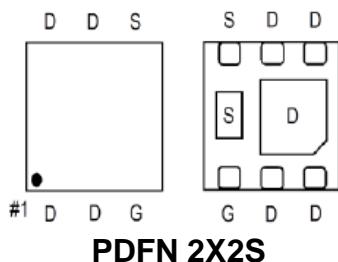


PB521BX

P-Channel Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-20V	21mΩ @ $V_{GS} = -4.5V$	-7.4A



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 8	
Continuous Drain Current $T_A = 25^\circ C$ $T_A = 70^\circ C$	I_D	-8	A
		-6.4	
Pulsed Drain Current ¹	I_{DM}	29	
Power Dissipation $T_A = 25^\circ C$ $T_A = 70^\circ C$	P_D	2.1	W
		1.4	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$		57	°C / W

¹Pulse width limited by maximum junction temperature.

²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper.

PB521BX P-Channel Enhancement Mode MOSFET

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

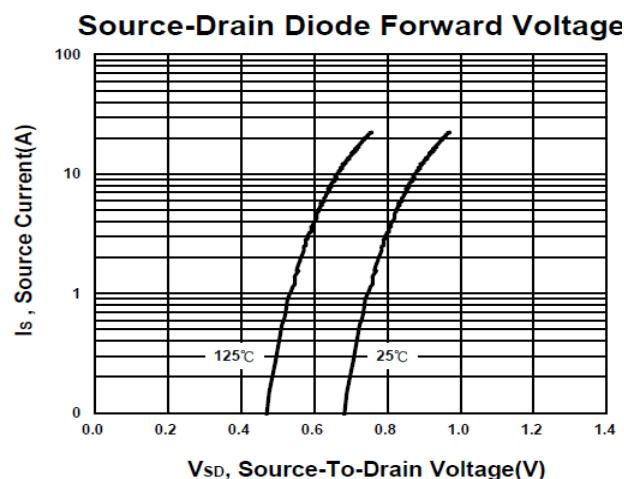
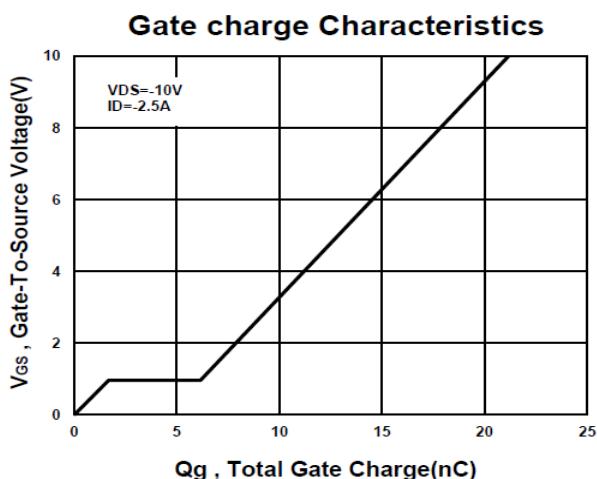
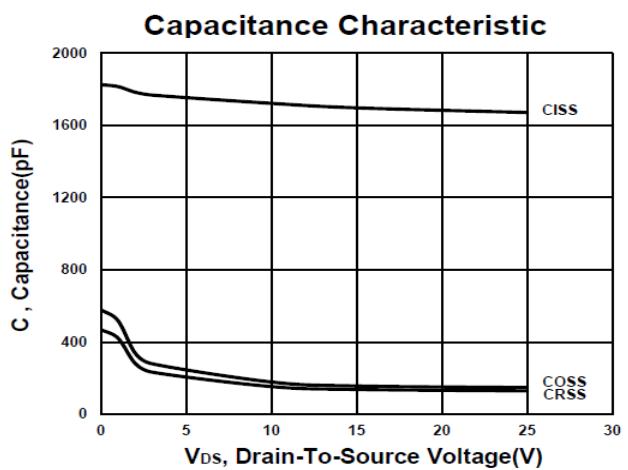
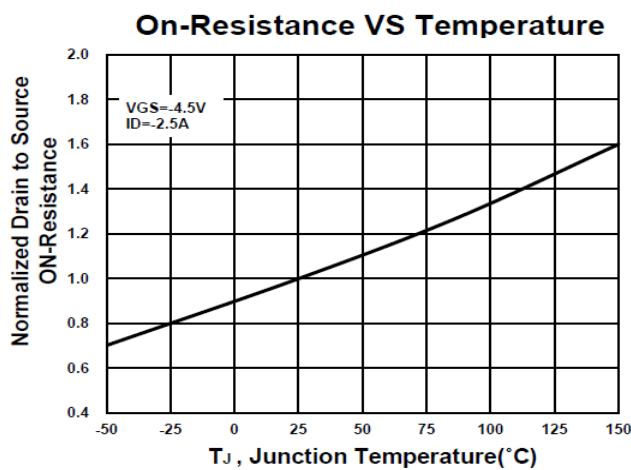
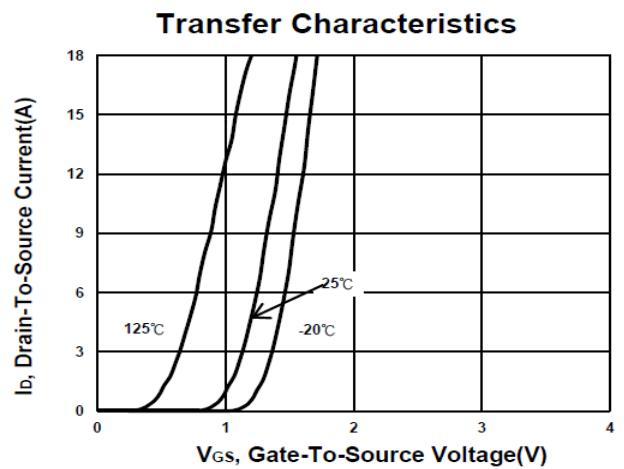
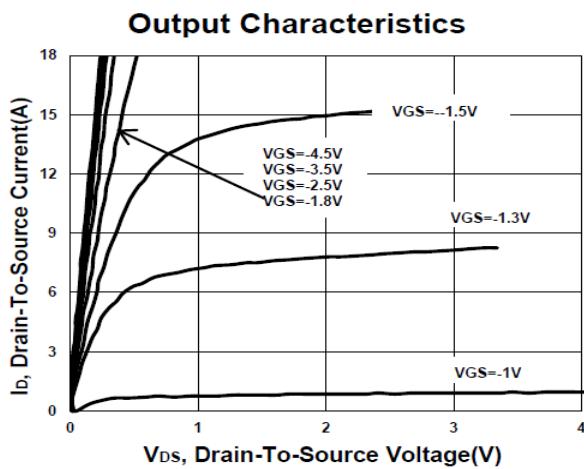
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-20			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-0.45	-0.6	-0.85	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 8\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -16\text{V}, V_{\text{GS}} = 0\text{V}$			-1	μA
		$V_{\text{DS}} = -10\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			-10	
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -1.8\text{V}, I_D = -1\text{A}$		24	40	$\text{m}\Omega$
		$V_{\text{GS}} = -2.5\text{V}, I_D = -2\text{A}$		19	28	
		$V_{\text{GS}} = -4.5\text{V}, I_D = -2.5\text{A}$		15	21	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = -10\text{V}, I_D = -2.5\text{A}$		21		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -10\text{V}, f = 1\text{MHz}$		1727		pF
Output Capacitance	C_{oss}			179		
Reverse Transfer Capacitance	C_{rss}			155		
Gate Resistance	R_g	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		10		Ω
Total Gate Charge ²	Q_g	$V_{\text{DS}} = -10\text{V}, V_{\text{GS}} = -4.5\text{V}, I_D = -2.5\text{A}$		21		nC
Gate-Source Charge ²	Q_{gs}			1.8		
Gate-Drain Charge ²	Q_{gd}			4.9		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -10\text{V}$ $I_D \approx -2.5\text{A}, V_{\text{GEN}} = -4.5\text{V}, R_G = 6\Omega$		28		nS
Rise Time ²	t_r			21		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			81		
Fall Time ²	t_f			48		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				-1.7	A
Forward Voltage ¹	V_{SD}	$I_F = -2.5\text{A}, V_{\text{GS}} = 0\text{V}$			-1.2	V
Reverse Recovery Time	t_{rr}	$I_F = -2.5\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		35		nS
Reverse Recovery Charge	Q_{rr}			18		nC

¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

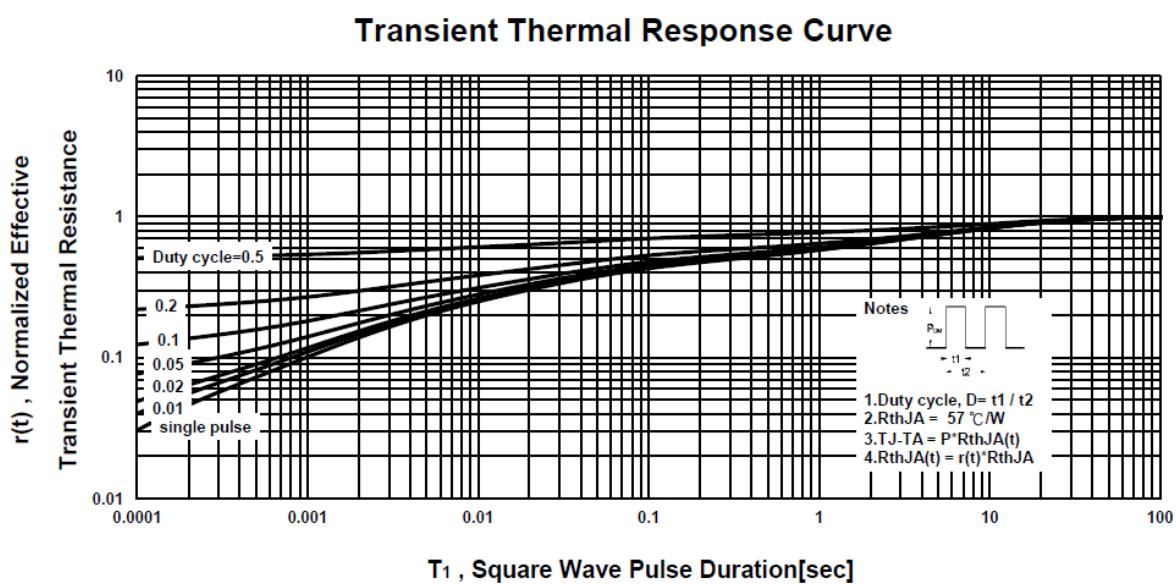
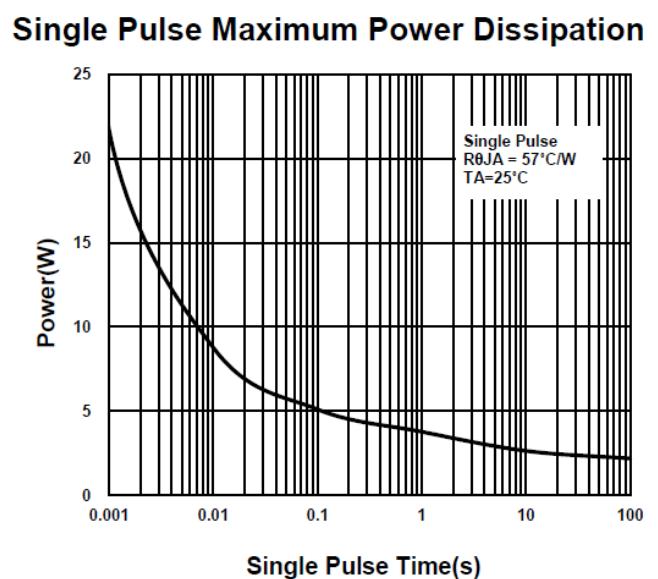
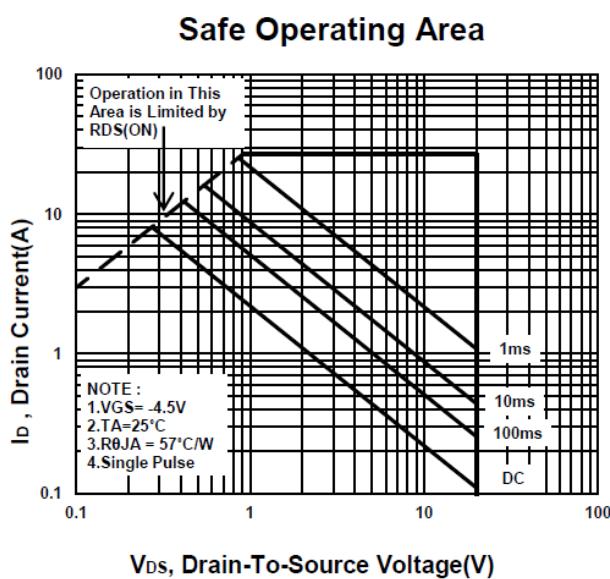
PB521BX

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Package Dimension

PDFN 2x2S MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	1.9		2.1	I	0		0.05
B	1.9		2.1	J		0.203	
C	0.55	0.65	0.75	K	0.55		0.8
D	0.85		1.25	L	0.2		0.4
E	0.174	0.25	0.326	M	0.46		0.85
F	0.25		0.35	N		0.15	
G		0.2		O		0.23	
H	0.8		1.15				

